

Description

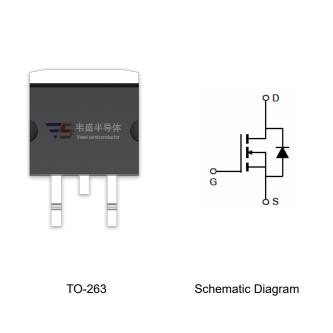
The VST10N030 uses **Super Trench** technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{DS(ON)}$ and Q_g . This device is ideal for high-frequency switching and synchronous rectification.

General Features

- $V_{DS} = 100V, I_D = 150A$ $R_{DS(ON)} < 3.6 m\Omega @ V_{GS} = 10V$
- Excellent gate charge x R_{DS(on)} product
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating
- 100% UIS tested

Application

- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VST10N030-T3	VST10N030	TO-263	-	-	-

Absolute Maximum Ratings (T_c=25°Cunless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	100	V	
Gate-Source Voltage	V _G s	±20	V	
Drain Current-Continuous (Silicon Limited)	I _D	170	А	
Drain Current-Continuous (Package Limited)	I _D	150	А	
Drain Current-Continuous(T _C =100 °C)	I _D (100°C)	120	А	
Pulsed Drain Current	I _{DM}	600	А	
Maximum Power Dissipation	P _D	250	W	
Derating factor		1.67	W/℃	
Single pulse avalanche energy (Note 5)	E _{AS}	1500	mJ	
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}$ C	

Thermal Characteristic

Thermal Resistance,Junction-to-Case ^(Note 2)	$R_{ heta JC}$	0.6	°C/W
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Electrical Characteristics (T_C=25[°]Cunless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics				•		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	100		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V,V _{GS} =0V	-	-	1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)				•		
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.5	3.5	4.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =75A	-	3.0	3.6	mΩ
Forward Transconductance	G FS	V _{DS} =10V,I _D =75A	75	-	-	S
Dynamic Characteristics (Note4)				•		
Input Capacitance	C _{lss}	V _{DS} =50V,V _{GS} =0V,	-	7770	-	PF
Output Capacitance	C _{oss}		-	795	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	46	-	PF
Switching Characteristics (Note 4)				•		
Turn-on Delay Time	t _{d(on)}		-	25	-	nS
Turn-on Rise Time	t _r	V_{DD} =50 V , I_D =75 A	-	80	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10 V , R_{G} =4.7 Ω	-	52	-	nS
Turn-Off Fall Time	t _f		-	17	-	nS
Total Gate Charge	Qg	\/ _50\/1 _75A	-	113		nC
Gate-Source Charge	Q _{gs}	V_{DS} =50V, I_{D} =75A, V_{GS} =10V	-	39.5		nC
Gate-Drain Charge	Q _{gd}		-	25.6		nC
Drain-Source Diode Characteristics			•	•		
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =150A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	150	Α
Reverse Recovery Time	t _{rr}	$T_J = 25$ °C, $I_F = I_S$	-	75		nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	168		nC

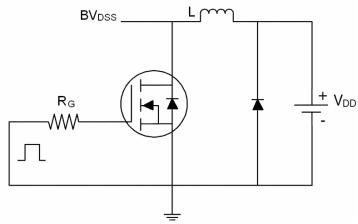
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition : Tj=25 $^{\circ}\text{C}$,V_DD=50V,V_G=10V,L=0.5mH,Rg=25 Ω

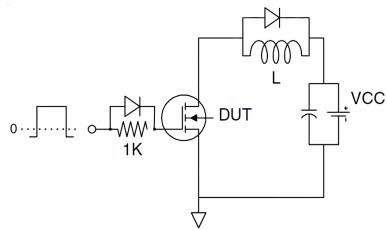


Test Circuit

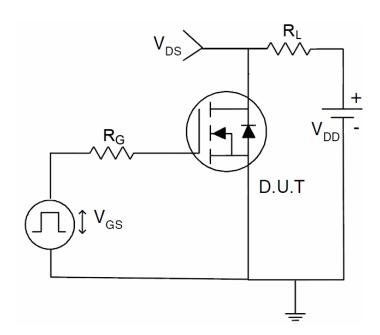
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit







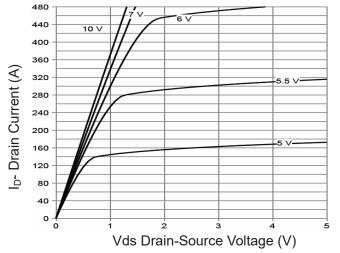


Figure 1 Output Characteristics

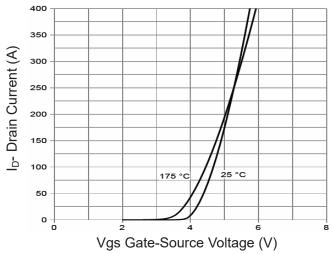


Figure 2 Transfer Characteristics

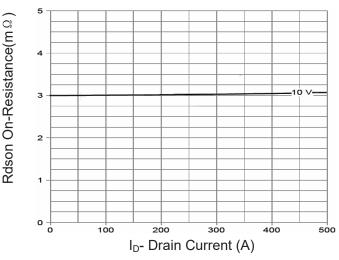


Figure 3 Rdson-Drain Current

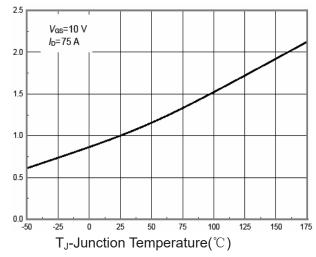


Figure 4 Rdson-JunctionTemperature

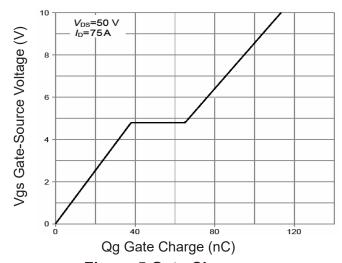


Figure 5 Gate Charge

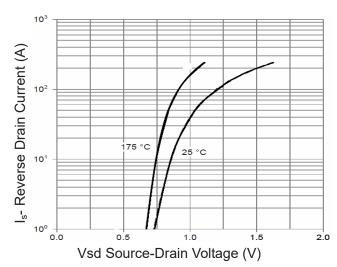


Figure 6 Source- Drain Diode Forward



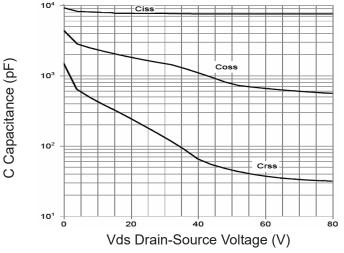


Figure 7 Capacitance vs Vds

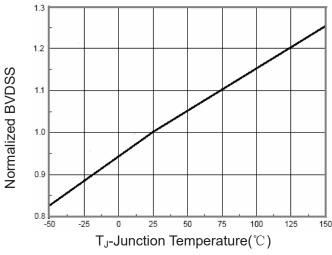


Figure 9 BV_{DSS} vs Junction Temperature

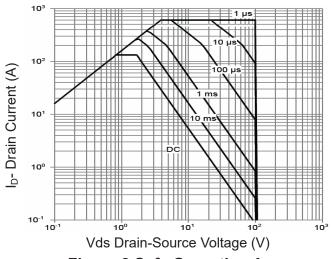


Figure 8 Safe Operation Area

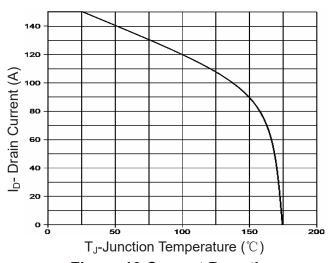


Figure 10 Current De-rating

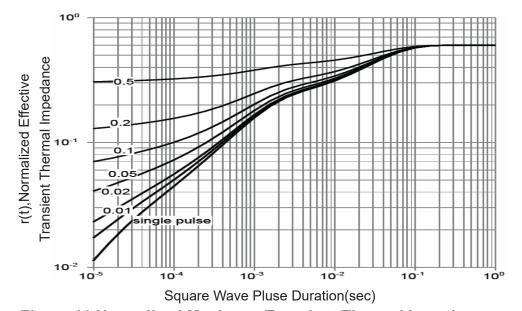


Figure 11 Normalized Maximum Transient Thermal Impedance